

<b>Notice of References Cited</b>	Application/Control No. 10/812,309	Applicant(s)/Patent Under Reexamination MCLAURIN ET AL.	
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	W	McLaurin et al., "The Testability Features of the MCF5407 Containing the 4th Generation ColdFire Microprocessor Core", IEEE, 2000.
	X	McLaurin et al., "On-the-Shelf Core Pattern Methodology for ColdFire Microprocessor Cores", IEEE 2000.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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